



IEEE Product Safety Engineering Society Santa Clara Valley Chapter

Chair: Ken Kapur, kapur@ieee.org
Vice-Chair: Kevin Ravo, kevin.l.ravo@ul.com
Treasurer: Jon Derickson, jsderickson@google.com
Secretary: Trish Bass, trish.bass@lewisbass.com

June MEETING

Update on IEC 62368-1, AV/ITE Legacy Standards & Related Topics

Meeting Date: Tuesday, June 25, 2013

Dinner: 5:15 –6:45 pm

Socialize with your colleagues and tonight's speaker at:

Honba Sushi

2587 North 1st St
San Jose, CA 95131, (408) 428-9770
No RSVP required.

Meeting Site:

UL LLC (Underwriters Laboratories)
455 E. Trimble Rd.
San Jose, CA 95131

Virtual Access:

A WebEx link and Dial In number will be provided as well prior to the meeting for those who are unable to attend in person. Please watch for this about one week prior to the meeting.

Presentation: 7:00 – 8:30 pm

Abstract:

As follow-on to his June 2012 presentation to the Chapter, Tom Burke will provide an update on the current status of IEC 62368-1, including updates on Edition No. 2 publication, overview of the type of changes between Editions 1 & 2, and current information on likely adoption and transition scenarios, including North America and Europe. Tom also will be giving the status of the legacy standards, IEC 60950-1 (ITE) and IEC 60065 (AV) since new (and final) versions of these standards are being issued too. There will be adequate time allocated for Q&A and audience perspectives on the pending transition.

Speaker:

Tom Burke
Principal Engineer - ICT/High Tech
UL LLC

For a complete bio on Tom, please see Tom's profile on LinkedIn: <http://www.linkedin.com/pub/thomas-burke-pe/29/535/567> , and consider joining UL's LinkedIn HBSE Group, where Tom makes frequent contributions: http://www.linkedin.com/groups?gid=4078620&trk=myg_ugrp_ovr.

Notes:

- 1: Please don't forget to share/forward this to others who might be interested in the PSES or in this particular subject!**
- 2: If you are not an IEEE Member, please go to: <http://ewh.ieee.org/soc/pses/> for more information about the IEEE PSES and how to join.**